PERFORMANCE CHECKSHEET

Model: AVR-EB4-B-ANB-VXI-X2-SMA-AC03-ATA3
Type: Semiconductor Device Tester
S.N.: 13121
Date: February 26, 2014

Basic specifications: →

Output Amplitude: to +2A, -4A
Pulse Width (FWHM): 2 – 20 us
Switching Time, + to -, 10%-90%: ≤ 4.5 ns
PRF: 1 - 100 Hz
Jitter, Stability: OK
Prime Power: 100-240V AC, 50-60 Hz.

Test Waveforms

With an On Semi 1N4937 (date code 1037) installed in the AVX-TRR-ANB (S/N 13121) test jig, connected using the 60 cm / 24" coaxial cable:

\[ I_F = +2A, \ I_R = -4A, \ I_{RR} = -1A. \]
100 Hz, 20 us PW.
5V (1A) / div, 40 ns/div.
Measured \( t_{RR} = 97.6 \) ns.

With a generic 1N4004 installed in the AVX-TRR-ANB (S/N 13122) test jig, connected using the 60 cm / 24" coaxial cable:

\[ I_F = +2A, \ I_R = -4A, \ I_{RR} = -1A. \]
100 Hz, 20 us PW.
5V (1A) / div, 400 ns/div.
Measured \( t_{RR} = 0.96 \) us.
With a Microsemi MQ1N5811US installed in the AVX-TRR-SQMELF test jig (S/N 13123), connected using the 60 cm / 24" coaxial cable:

If $I_c = +0.5A$, $I_R = -1A$, $I_{RR} = -0.25A$.

100 Hz, 20 us PW.

2V (0.4A) / div, 20 ns/div.

Measured $t_{RR} = 22.4$ ns.

Mainframe output, with a zero Ohm jumper installed in the AVX-TRR-ANB (S/N 13121) test jig:

50 V / div, 20 ns/div. +100V, -200V.

10% - 90% fall time shown.